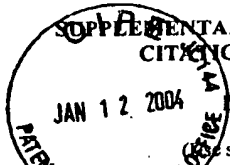



PTO-1449 REPRODUCED		ATTORNEY DOCKET NO. 3243.1000-001		APPLICATION NO. 10/073,678			
INFORMATION DISCLOSURE CITATION IN AN APPLICATION June 5, 2002 (Use several sheets if necessary)		APPLICANT Christina Lampe-Onnerud, et al.					
		FILING DATE February 11, 2002		GROUP 1745			
<b>U.S. PATENT DOCUMENTS</b>							
EXAM- INER INI- TIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO
LSW	AL	11-195416	21-JUL-99	Japan			Abstract
	AM	<del>11-195416</del>	<del>21-JUL-99</del>	<del>Japan (Abstract)</del>			
LSW	AN	09-17430	17-JAN-97	Japan (Abstract)			
LSW	AO	10-236826	1998	Japan (Abstract)			
LSW	AP	09-50810	18-FEB-97	Japan (Abstract)			
LSW	AQ	07-235292	05-SEP-95	Japan (Abstract)			
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LSW	AO2	08-315819	29-NOV-96	Japan (Abstract)			
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	AR						
	AS						
EXAMINER <i>James W. Weir</i>				DATE CONSIDERED <i>1-15-04</i>			



PTO-1449 REPRODUCED		ATTORNEY DOCKET NO. 3243.1000-001		APPLICATION NO. 10/073,678	
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		EXAMINER Not Yet Assigned		CONFIRMATION NO. 4567	
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EXAMINER 	DATE CONSIDERED 3-25-04
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